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INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application Number	Unknown 10-789890.		
(Use as many sheets as necessary)	Filing Date	Even Date Herewith 227/04		
	First Named Inventor	Schuegraf, Klaus		
·	Group Art Unit	-Unknown 2825		
	Examiner Name	Unknown Lee		
Sheet 1 of 2	Attorney Docket No: 3	303.278US2		

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	Filing Date	Even Date Herewith 2 27 04				
•	First Named Inventor	Schuegraf, Klaus				
	Group Art Unit	Unknown 2825				
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